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Lithium tantalate and lithium niobate crystals for surface acoustic wave (SAW) device applications - Specifications and measuring methods

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Lithium tantalate and lithium niobate crystals for surface acoustic wave (SAW) device applications - Specifications and measuring methods

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The text of this International Standard is based on the following documents:

Draft	Report on voting
49/1496/CDV	49/1517/RVC

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

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– withdrawn, or
– revised.

1 Scope

This document applies to lithium tantalate (LT) and lithium niobate (LN) crystals for surface acoustic wave devices, including the as-grown crystals and lumbered crystals.

2 Normative references

There are no normative references in this document.

Bibliography

IEC 62276:2025, *Single crystal wafers for surface acoustic wave (SAW) device applications - Specifications and measuring methods*

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